

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)				ATTY. DOCKET NO. LBP-PT033		SERIAL NO. 10766,463		
				APPLICANT Rembe et al.				
				FILING DATE January 28, 2004		GROUP 2877		
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
life	AA	6,084,672	07/04/00	Andrew Lewin	1	1		
life	AB	6,404,545	06/11/02	Hiroshi Ishiwata	1	1		
life	AC	6,181,431	01/30/01	Bernard Siu	1	1		
life	AD	US 2002/089740	07/11/02	Jeffrey A. Beckstead- Wetzel et al.	1	1		
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
life	AE	JP 61-013233	01/86	Japan - Abstract	1	1		
life	AF	WO 00/33727	06/00	PCT	1	1		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
life	AG	Q. S. Davis et al., "Using a Light Microscope to Measure Motions with Nanometer Accuracy", Optical Engineering, Vol. 37, 1998, pp. 1299-1304						
life	AH	N. F. Smith et al., "Non-Destructive Resonant Frequency Measurements on MEMS Actuators", Proc. of IEEE 01CH37167, 39th Annual Internat'l Reliability Physics Symposium, Orlando, FL 2001, pp. 99-103						
life	AI	Microscope Scanning Vibrometer MSV 300, Polytec Hardware Manual for Scanner Controller MSV-Z-040,						
		Microscope Adapter OFV-074 and Scanner Unit OFV-073, Polytec GmbH, Waldbronn, Germany 2002						

EXAMINER <i>Paul J. Charles</i>	DATE CONSIDERED <i>9/22/05</i>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.